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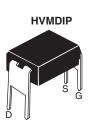
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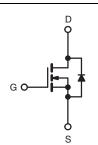
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### **Power MOSFET**

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	100			
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = 5.0 V 0.27			
Q <sub>g</sub> (Max.) (nC)	12			
Q <sub>gs</sub> (nC)	3.0			
Q <sub>gd</sub> (nC)	7.1			
Configuration	Single			





N-Channel MOSFET

#### **FEATURES**

- · Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- For Automatic Insertion
- End Stackable
- · Logic-Level Gate Drive
- R<sub>DS(on)</sub> Specified at V<sub>GS</sub> = 4 V and 5 V
- 175 °C Operating Temperature
- Compliant to RoHS Directive 2002/95/EC

#### **DESCRIPTION**

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The 4 pin DIP package is a low cost machine-insertable case style which can be stacked in multiple combinations on standard 0.1" pin centers. The dual drain serves as a thermal link to the mounting surface for power dissipation levels up to 1 W.

ORDERING INFORMATION			
Package	HVMDIP		
Lead (Pb)-free	IRLD120PbF		
Lead (PD)-liee	SiHLD120-E3		
SnPb	IRLD120		
Sili b	SiHLD120		

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>A</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	100	V	
Gate-Source Voltage			$V_{GS}$	± 10	V	
Continuous Drain Current	$V_{GS}$ at 5.0 V $T_A = 25 ^{\circ}\text{C}$ $T_A = 100 ^{\circ}\text{C}$	,	1.3			
Continuous Drain Current		T <sub>A</sub> = 100 °C	I <sub>D</sub>	0.94	А	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	10	1	
Linear Derating Factor				0.0083	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	690	mJ	
Avalanche Current <sup>a</sup>			I <sub>AR</sub>	1.3	Α	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	0.13	mJ	
Maximum Power Dissipation T <sub>A</sub> = 25 °C		$P_{D}$	1.3	W		
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	5.5	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	- °C	
Soldering Recommendations (Peak Temperature)	for	for 10 s		300 <sup>d</sup>	7	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD}$  = 25 V, starting  $T_J$  = 25 °C, L = 153 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 2.6 A (see fig. 12). c.  $I_{SD}$  ≤ 9.2 A, dI/dt ≤ 110 A/ $\mu$ s,  $V_{DD}$  ≤  $V_{DS}$ ,  $V_{DS}$  = 175 °C.
- d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply

## IRLD120, SiHLD120

## Vishay Siliconix



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	$R_{thJA}$	=	120	°C/W	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static					l		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	100	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.12	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	· V <sub>GS</sub> , I <sub>D</sub> = 250 μA	1.0	-	2.0	V
Gate-Source Leakage	I <sub>GSS</sub>	,	V <sub>GS</sub> = ± 10 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V		-	25	, , ,
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 80 V	V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C	-	-	250	μΑ
Drain-Source On-State Resistance	Ъ	V <sub>GS</sub> = 5.0 V	I <sub>D</sub> = 0.78 A <sup>b</sup>	-	-	0.27	Ω
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.0 V	I <sub>D</sub> = 0.65 A <sup>b</sup>	-	-	0.38	
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	50 V, I <sub>D</sub> = 0.78 A <sup>b</sup>	1.9	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	-	490	-	
Output Capacitance	C <sub>oss</sub>	]	$V_{DS} = 25 \text{ V},$	-	150	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.	0 MHz, see fig. 5	-	30	-	
Total Gate Charge	Qg			-	-	12	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 5.0 V	$I_D = 9.2 \text{ A}, V_{DS} = 80 \text{ V},$ see fig. 6 and 13 <sup>b</sup>	-	-	3.0	
Gate-Drain Charge	$Q_{gd}$		goo ngi o ana 10	-	-	7.1	
Turn-On Delay Time	t <sub>d(on)</sub>			-	9.8	-	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> -	= 50 V, I <sub>D</sub> = 9.2 A,	-	64	-	ne
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_{g} = 9.0 \ \Omega, \ R_{D} = 5.2 \ \Omega, \ \text{see fig. } 10^{b}$		-	21	-	ns
Fall Time	t <sub>f</sub>			-	27	-	
Internal Drain Inductance	L <sub>D</sub>		Between lead, 6 mm (0.25") from		4.0	-	-11
Internal Source Inductance	L <sub>S</sub>	package and center of die contact		-	6.0	-	nH
Drain-Source Body Diode Characteristic	s				l		
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET sym	MOSFET symbol showing the		-	1.3	^
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	10	A
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 1.3 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	-	2.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T 05.00 :	0.0.4 11/11 400.67	-	130	140	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25  ^{\circ}\text{C}$ , $I_F = 9.2  \text{A}$ , $dI/dt = 100  \text{A}/\mu \text{s}^b$		-	0.83	1.0	μС
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )				L <sub>D</sub> )	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

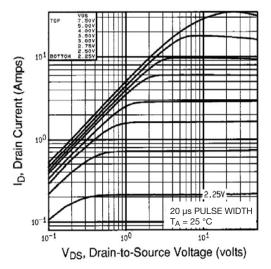


Fig. 1 - Typical Output Characteristics,  $T_A$  = 25 °C

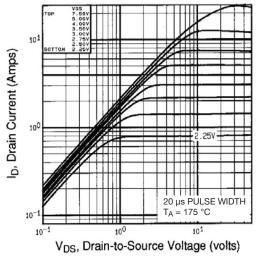


Fig. 2 - Typical Output Characteristics,  $T_A$  = 175 °C

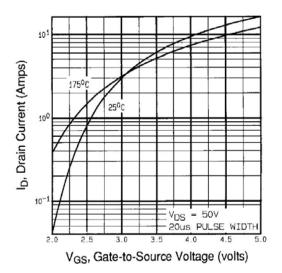


Fig. 3 - Typical Transfer Characteristics

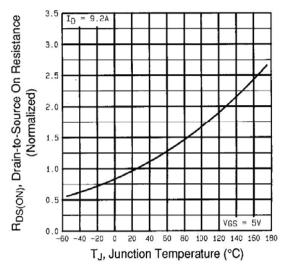


Fig. 4 - Normalized On-Resistance vs. Temperature



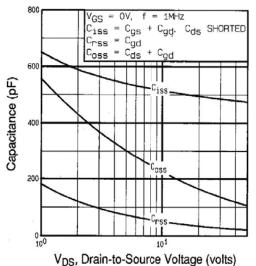


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

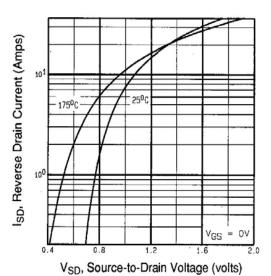


Fig. 7 - Typical Source-Drain Diode Forward Voltage

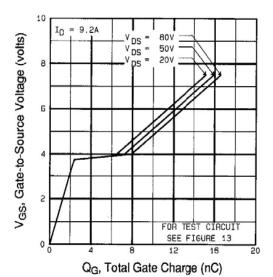


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

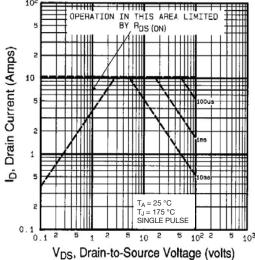


Fig. 8 - Maximum Safe Operating Area





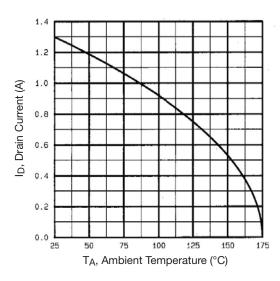


Fig. 9 - Maximum Drain Current vs. Ambient Temperature

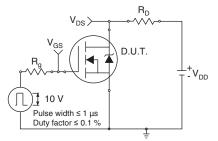


Fig. 10a - Switching Time Test Circuit

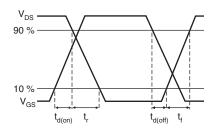


Fig. 10b - Switching Time Waveforms

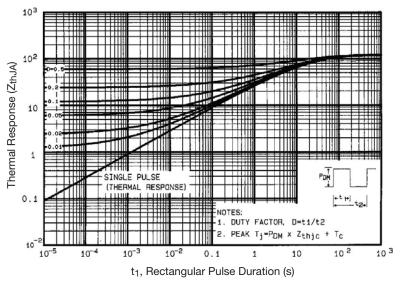


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Ambient



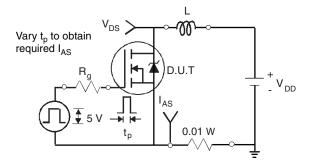


Fig. 12a - Unclamped Inductive Test Circuit

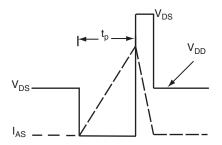


Fig. 12b - Unclamped Inductive Waveforms

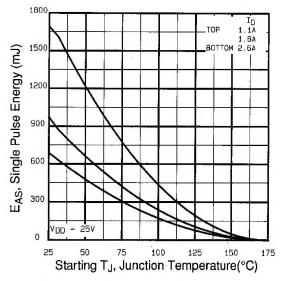


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

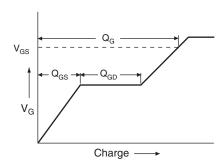


Fig. 13a - Basic Gate Charge Waveform

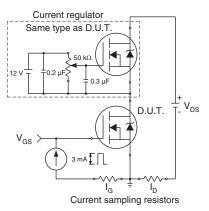
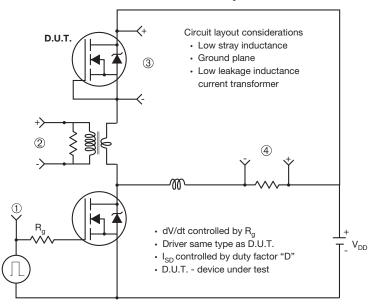


Fig. 13b - Gate Charge Test Circuit





#### Peak Diode Recovery dV/dt Test Circuit



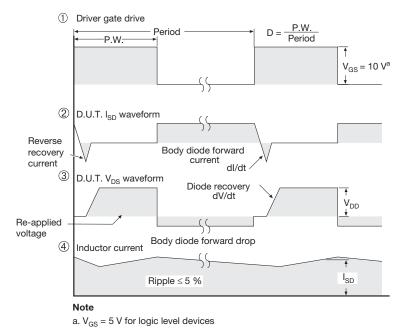
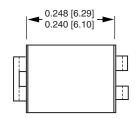
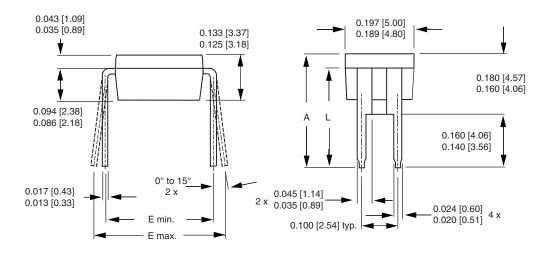


Fig. 14 - For N-Channel

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#### **HVM DIP** (High voltage)





	INCHES		MILLIMETERS	
DIM.	MIN.	MAX.	MIN.	MAX.
А	0.310	0.330	7.87	8.38
E	0.300	0.425	7.62	10.79
L	0.270	0.290	6.86	7.36

ECN: X10-0386-Rev. B, 06-Sep-10

DWG: 5974

1. Package length does not include mold flash, protrusions or gate burrs. Package width does not include interlead flash or protrusions.

Document Number: 91361 Revision: 06-Sep-10



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